BDTIC www.BDTIC.com/ATMEL

1. Features

Low-voltage and Standard-voltage Operation

- 1.8 (V_{CC} = 1.8V to 5.5V)

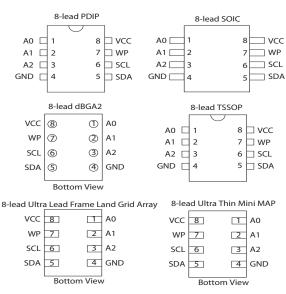
- Internally Organized as 16,384 x 8
- Two-wire Serial Interface
- Schmitt Trigger, Filtered Inputs for Noise Suppression
- Bidirectional Data Transfer Protocol
- 1 MHz (5.5V, 2.5V), and 400 kHz (1.8V) Compatibility
- Write Protect Pin for Hardware and Software Data Protection
- 64-byte Page Write Mode (Partial Page Writes Allowed)
- Self-timed Write Cycle (5 ms Max)
- High Reliability
 - Endurance: One Million Write Cycles
 - Data Retention: 40 Years
- Lead-free/Halogen-free
- 8-lead JEDEC PDIP, 8-lead JEDEC SOIC, 8-lead Ultra Thin Mini MAP, 8-lead Ultra Lead Frame Land Grid Array (ULA), 8-lead TSSOP, and 8-ball dBGA2 Packages
- Die Sales: Wafer Form, Tape and Reel and Bumped Wafers

2. Description

The AT24C128B provides 131,072 bits of serial electrically erasable and programmable read-only memory (EEPROM) organized as 16,384 words of 8 bits each. The device's cascadable feature allows up to eight devices to share a common two-wire bus. The device is optimized for use in many industrial and commercial applications where low-power and low-voltage operation are essential. The devices are available in space-saving 8-lead JEDEC PDIP, 8-lead JEDEC SOIC, 8-lead Ultra Thin Mini MAP, 8-lead Ultra Lead Frame Land Grid Array (ULA), 8-lead TSSOP, and 8-ball dBGA2 packages. In addition, the entire family is available in a 1.8V (5.5V to 3.6V) version.

Table 0-1. Pin Configurations

Pin Name	Function
A0–A2	Address Inputs
SDA	Serial Data
SCL	Serial Clock Input
WP	Write Protect
GND	Ground





Two-wire Serial EEPROM

128K (16,384 x 8)

AT24C128B

Rev. 5296A-SEEPR-1/08





Absolute Maximum Ratings* 3.

Operating Temperature55°C to +125°C
Storage Temperature65°C to +150°C
Voltage on Any Pin with Respect to Ground1.0V to +7.0V
Maximum Operating Voltage 6.25V
DC Output Current 5.0 mA

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

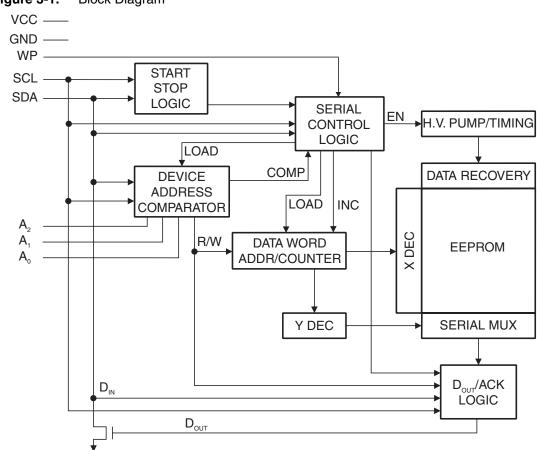


Figure 3-1. Block Diagram

AT24C128B 2

4. Pin Description

SERIAL CLOCK (SCL): The SCL input is used to positive-edge clock data into each EEPROM device and negative-edge clock data out of each device.

SERIAL DATA (SDA): The SDA pin is bidirectional for serial data transfer. This pin is opendrain driven and may be wire-ORed with any number of other open-drain or open-collector devices.

DEVICE/PAGE ADDRESSES (A2, A1, A0): The A2, A1, and A0 pins are device address inputs that are hardwired (directly to GND or to Vcc) for compatibility with other AT24Cxx devices. When the pins are hardwired, as many as eight 128K devices may be addressed on a single bus system. (Device addressing is discussed in detail under "Device Addressing," page 8.) A device is selected when a corresponding hardware and software match is true. If these pins are left floating, the A2, A1, and A0 pins will be internally pulled down to GND. However, due to capacitive coupling that may appear during customer applications, Atmel recommends always connecting the address pins to a known state. When using a pull-up resistor, Atmel recommends using $10k\Omega$ or less.

WRITE PROTECT (WP): The write protect input, when connected to GND, allows normal write operations. When WP is connected directly to Vcc, all write operations to the memory are inhibited. If the pin is left floating, the WP pin will be internally pulled down to GND. However, due to capacitive coupling that may appear during customer applications, Atmel recommends always connecting the WP pins to a known state. When using a pull-up resistor, Atmel recommends using $10k\Omega$ or less.





5. Memory Organization

AT24C128B, 128K SERIAL EEPROM: The 128K is internally organized as 256 pages of 64 bytes each. Random word addressing requires a 14-bit data word address.

Table 5-1.Pin Capacitance⁽¹⁾

Applicable over recommended operating range from $T_A = 25^{\circ}C$, f = 1.0 MHz, $V_{CC} = +1.8V$ to 5.5V

Symbol	Test Condition	Max	Units	Conditions
C _{I/O}	Input/Output Capacitance (SDA)	8	pF	$V_{I/O} = 0V$
C _{IN}	Input Capacitance (A ₀ , A ₁ , SCL)	6	pF	$V_{IN} = 0V$

Note: 1. This parameter is characterized and is not 100% tested.

Table 5-2.DC Characteristics

Applicable over recommended operating range from: $T_{AI} = -40^{\circ}C$ to $+85^{\circ}C$, $V_{CC} = +1.8V$ to +5.5V (unless otherwise noted)

Symbol	Parameter	Test Condition	Test Condition		Тур	Мах	Units
V _{CC1}	Supply Voltage			1.8		5.5	V
I _{CC1}	Supply Current	$V_{CC} = 5.0V$	READ at 400 kHz		1.0	2.0	mA
I _{CC2}	Supply Current	$V_{CC} = 5.0V$	WRITE at 400 kHz		2.0	3.0	mA
	Standby Current	$V_{CC} = 1.8V$				1.0	μA
I _{SB1}	(1.8V option)	$V_{\rm CC} = 5.5V$ $V_{\rm IN} = V_{\rm CC} \text{ or } V_{\rm SS}$				6.0	μA
I _{LI}	Input Leakage Current V _{CC} = 5.0V	$V_{IN} = V_{CC} \text{ or } V_{SS}$			0.10	3.0	μA
I _{LO}	Output Leakage Current V _{CC} = 5.0V	$V_{OUT} = V_{CC} \text{ or } V_{SS}$			0.05	3.0	μA
V _{IL}	Input Low Level ⁽¹⁾					V _{CC} x 0.3	V
V _{IH}	Input High Level ⁽¹⁾			V _{CC} x 0.7		V _{CC} + 0.5	V
V _{OL2}	Output Low Level	$V_{\rm CC} = 3.0 V$	I _{OL} = 2.1 mA			0.4	V
V _{OL1}	Output Low Level	$V_{CC} = 1.8V$	I _{OL} = 0.15 mA			0.2	V

Notes: 1. V_{IL} min and V_{IH} max are reference only and are not tested.

Table 5-3. AC Characteristics (Industrial Temperature)

Applicable over recommended operating range from $T_{AI} = -40^{\circ}$ C to $+85^{\circ}$ C, $V_{CC} = +1.8$ V to $+5.5$ V, CL = 100 pF (unless otherwise)
erwise noted). Test conditions are listed in Note 2.

		1	.8-volt	2.5,	2.5, 5.5-volt	
Symbol	Parameter	Min	Max	Min	Max	Units
f _{SCL}	Clock Frequency, SCL		400		1000	kHz
t _{LOW}	Clock Pulse Width Low	1.3		0.4		μs
t _{HIGH}	Clock Pulse Width High	0.6		0.4		μs
t _i	Noise Suppression Time ⁽¹⁾		100		50	ns
t _{AA}	Clock Low to Data Out Valid	0.05	0.9	0.05	0.55	μs
t _{BUF}	Time the bus must be free before a new transmission can start ⁽¹⁾			0.5		μs
t _{HD.STA}	Start Hold Time	0.6		0.25		μs
t _{SU.STA}	Start Set-up Time	0.6	0.6			μs
t _{HD.DAT}	Data In Hold Time	0	0			μs
t _{SU.DAT}	Data In Set-up Time	100	100			ns
t _R	Inputs Rise Time ⁽¹⁾		0.3		0.3	μs
t _F	Inputs Fall Time ⁽¹⁾		300		100	ns
t _{SU.STO}	Stop Set-up Time	0.6	0.6			μs
t _{DH}	Data Out Hold Time	50	50 50			ns
t _{wR}	Write Cycle Time		5		5	ms
Endurance ⁽¹⁾	25°C, Page Mode, 3.3V	1,000,000			Write Cycles	

Notes: 1. This parameter is ensured by characterization and is not 100% tested.

2. AC measurement conditions:

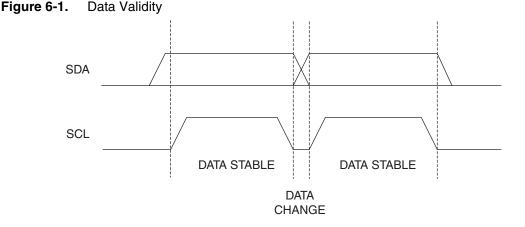
 $\rm R_L$ (connects to $\rm V_{CC}$): 1.3 k Ω (2.5V, 5.5V), 10 k Ω (1.8V) Input pulse voltages: 0.3 $\rm V_{CC}$ to 0.7 $\rm V_{CC}$ Input rise and fall times: \leq 50 ns Input and output timing reference voltages: 0.5 $\rm V_{CC}$

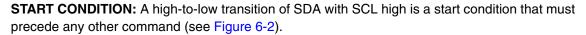
AMEL

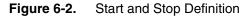


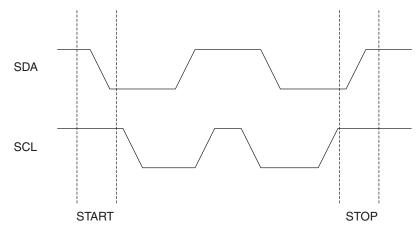
6. Device Operation

CLOCK and DATA TRANSITIONS: The SDA pin is normally pulled high with an external device. Data on the SDA pin may change only during SCL low time periods (see Figure 6-1). Data changes during SCL high periods will indicate a start or stop condition as defined below.









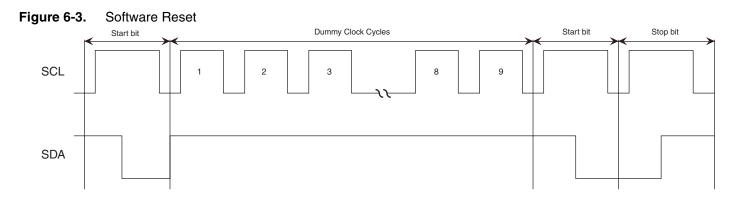
STOP CONDITION: A low-to-high transition of SDA with SCL high is a stop condition. After a read sequence, the stop command will place the EEPROM in a standby power mode (see Figure 6-2).

ACKNOWLEDGE: All addresses and data words are serially transmitted to and from the EEPROM in 8-bit words. The EEPROM sends a "0" during the ninth clock cycle to acknowledge that it has received each word.

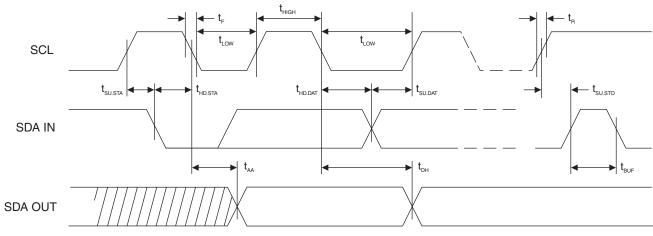
STANDBY MODE: The AT24C128B features a low-power standby mode that is enabled upon power-up and after the receipt of the stop bit and the completion of any internal operations.

SOFTWARE RESET: After an interruption in protocol, power loss or system reset, any 2-wire part can be protocol reset by following these steps: (a) Create a start bit condition, (b) clock 9

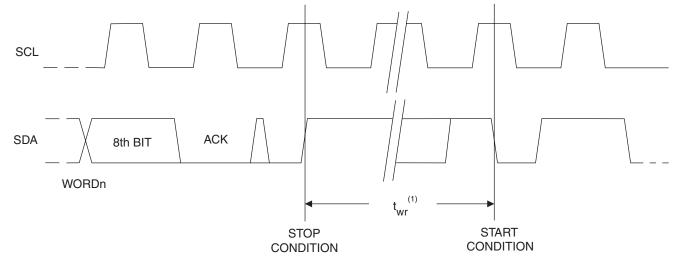
cycles, (c) create another start bit followed by stop bit condition as shown below. The device is ready for next communication after above steps have been completed.







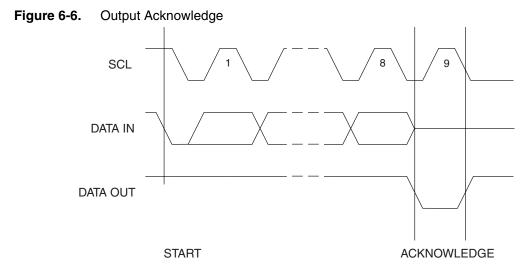




Note: 1. The write cycle time t_{WR} is the time from a valid stop condition of a write sequence to the end of the internal clear/write cycle.



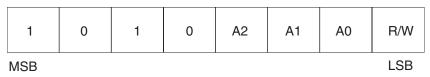




7. Device Addressing

The 128K EEPROM requires an 8-bit device address word following a start condition to enable the chip for a read or write operation (see Figure 7-1). The device address word consists of a mandatory "1", "0" sequence for the first four most significant bits as shown. This is common to all two-wire EEPROM devices.

FIGURE /-I. Device Address	Figure	7-1.	Device Address
----------------------------	--------	------	----------------



The next three bits are the A2, A1, A0 device address bits to allow as many as eight devices on the same bus. These bits must compare to their corresponding hardwired input pins. The A2, A1, and A0 pins use an internal proprietary circuit that biases them to a logic low condition if the pins are allowed to float.

The eighth bit of the device address is the read/write operation select bit. A read operation is initiated if this bit is high, and a write operation is initiated if this bit is low.

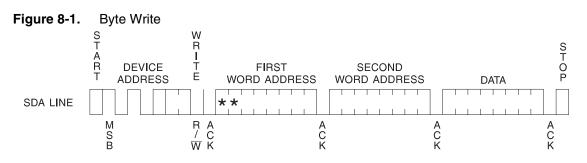
Upon a compare of the device address, the EEPROM will output a "0". If a compare is not made, the device will return to a standby state.

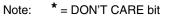
DATA SECURITY: The AT24C128B has a hardware data protection scheme that allows the user to write protect the whole memory when the WP pin is at V_{CC} .

8

8. Write Operations

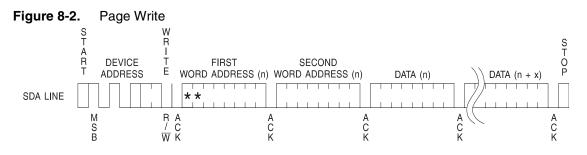
BYTE WRITE: A write operation requires two 8-bit data word addresses following the device address word and acknowledgment. Upon receipt of this address, the EEPROM will again respond with a "0" and then clock in the first 8-bit data word. Following receipt of the 8-bit data word, the EEPROM will output a "0". The addressing device, such as a microcontroller, must then terminate the write sequence with a stop condition. At this time the EEPROM enters an internally-timed write cycle, t_{WR}, to the nonvolatile memory. All inputs are disabled during this write cycle and the EEPROM will not respond until the write is complete (see Figure 8-1).





PAGE WRITE: The 128K EEPROM is capable of 64-byte page writes.

A page write is initiated the same way as a byte write, but the microcontroller does not send a stop condition after the first data word is clocked in. Instead, after the EEPROM acknowledges receipt of the first data word, the microcontroller can transmit up to 63 more data words. The EEPROM will respond with a "0" after each data word received. The microcontroller must terminate the page write sequence with a stop condition (see Figure 8-2).



Note: ***** = DON'T CARE bit

The data word address lower six bits are internally incremented following the receipt of each data word. The higher data word address bits are not incremented, retaining the memory page row location. When the word address, internally generated, reaches the page boundary, the following byte is placed at the beginning of the same page. If more than 64 data words are transmitted to the EEPROM, the data word address will "roll over" and previous data will be overwritten. The address "roll over" during write is from the last byte of the current page to the first byte of the same page.

ACKNOWLEDGE POLLING: Once the internally-timed write cycle has started and the EEPROM inputs are disabled, acknowledge polling can be initiated. This involves sending a start condition followed by the device address word. The read/write bit is representative of the operation desired. Only if the internal write cycle has completed will the EEPROM respond with a "0", allowing the read or write sequence to continue.



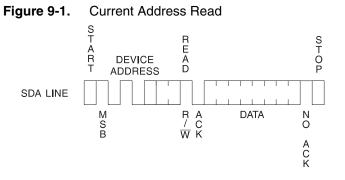


9. Read Operations

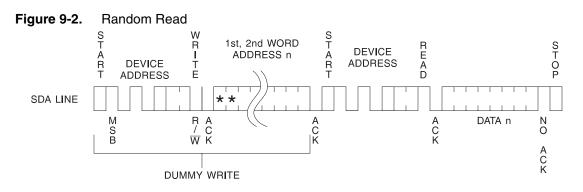
Read operations are initiated the same way as write operations with the exception that the read/write select bit in the device address word is set to "1". There are three read operations: current address read, random address read, and sequential read.

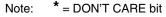
CURRENT ADDRESS READ: The internal data word address counter maintains the last address accessed during the last read or write operation, incremented by one. This address stays valid between operations as long as the chip power is maintained. The address "roll over" during read is from the last byte of the last memory page, to the first byte of the first page.

Once the device address with the read/write select bit set to "1" is clocked in and acknowledged by the EEPROM, the current address data word is serially clocked out. The microcontroller does not respond with an input "0" but does generate a following stop condition (see Figure 9-1).



RANDOM READ: A random read requires a "dummy" byte write sequence to load in the data word address. Once the device address word and data word address are clocked in and acknowledged by the EEPROM, the microcontroller must generate another start condition. The microcontroller now initiates a current address read by sending a device address with the read/write select bit high. The EEPROM acknowledges the device address and serially clocks out the data word. The microcontroller does not respond with a "0" but does generate a following stop condition (see Figure 9-2).





SEQUENTIAL READ: Sequential reads are initiated by either a current address read or a random address read. After the microcontroller receives a data word, it responds with an acknowledge. As long as the EEPROM receives an acknowledge, it will continue to increment the data word address and serially clock out sequential data words. When the memory address limit is reached, the data word address will "roll over" and the sequential read will continue. The

AT24C128B

sequential read operation is terminated when the microcontroller does not respond with a "0" but does generate a following stop condition (see Figure 9-3).

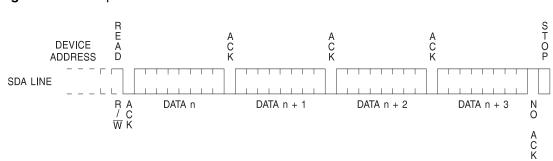


Figure 9-3. Sequential Read





10. AT24C128B Ordering Information

Ordering Code	Voltage	Package	Operation Range
AT24C128B-PU (Bulk Form Only)	1.8	8P3	
AT24C128BN-SH-B ⁽¹⁾ (NiPdAu Lead Finish)	1.8	8S1	
AT24C128BN-SH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8S1	
AT24C128B-TH-B ⁽¹⁾ (NiPdAu Lead Finish)	1.8	8A2	Lead-free/Halogen-free Industrial Temperature
AT24C128B-TH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8A2	(-40°C to 85°C)
AT24C128BY6-YH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8Y6	
AT24C128BD3-DH-T ⁽²⁾ (NiPdAu Lead Finish)	1.8	8D3	
AT24C128BU2-UU-T ⁽²⁾	1.8	8U2-1	
AT24C128B-W-11 ⁽³⁾	1.8	Die Sale	Industrial Temperature (-40°C to 85°C)

Notes: 1. "-B" denotes bulk.

2. "-T" denotes and tape and reel. SOIC = 4K. TSSOP, dBGA2, and Mini MAP = 5k. SAP = 3K.

3. Available in tape and reel and wafer form; order as SL788 for inkless wafer form. Bumped die available upon request. Please contact Serial Interface Marketing.

Package Type			
8P3	8-lead, 0.300" Wide, Plastic Dual Inline Package (PDIP)		
8S1	8-lead, 0.150" Wide, Plastic Gull Wing Small Outline Package (JEDEC SOIC)		
8A2	8-lead, 0.170" Wide, Thin Shrink Small Outline Package (TSSOP)		
8Y6	8-lead, 2.00 mm x 3.00 mm Body, 0.50 mm Pitch, Ultra Thin Mini MAP, Dual No Lead Package, (DFN), (MLP2x3mm)		
8D3	8-lead, 1.80 mm x 2.20 mm Body, Ultra Lead Frame Land Grid Array (ULA)		
8U2-1	8-ball, die Ball Grid Array Package (dBGA2)		
Options			
-1.8	Low-voltage (1.8V to 5.5V)		

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11. Part marking scheme

11.1 8-PDIP

TOP MARK	Seal Year
	Seal Week
A T M L U	Y W W
2 D B 1	
* Lot Number	
 Pin 1 Indicator (Dot	こ)

Y =	SEAL	YEAR		WW = SEAL WEEK
6:	2006	0:	2010	02 = Week 2
7:	2007	1:	2011	04 = Week 4
8:	2008	2:	2012	:: : :::: :
9:	2009	3:	2013	:: : :::: ::
				50 = Week 50
				52 = Week 52

Lot Number to Use ALL Characters in Marking

BOTTOM MARK

No Bottom Mark

11.2 8-SOIC

TOP MARK	Seal Year
	Seal Week
A T M L	H Y W W
2 D B	1
* Lot Number	
Pin 1 Indicator	(Dot)

Y =	SEAL	YEAR		WW = SEAL WEEK
6:	2006	0:	2010	02 = Week 2
7:	2007	1:	2011	04 = Week 4
8:	2008	2:	2012	:: : :::: :
9:	2009	3:	2013	:: : :::: ::
				50 = Week 50
				52 = Week 52

Lot Number to Use ALL Characters in Marking

BOTTOM MARK

No Bottom Mark





11.3 8-TSSOP

TOP MARK

Pin 1 Indicator (Dot)	Y = SEAL YEAR	WW = SEAL WEEK
I	6: 2006 0: 2010	02 = Week 2
	7: 2007 1: 2011	04 = Week 4
* H Y W W	8: 2008 2: 2012	:: : :::: :
	9: 2009 3: 2013	:: : :::: ::
2 D B 1 *		50 = Week 50
		52 = Week 52

BOTTOM MARK

				-	-	-
С	0	0				
				-	-	-
А	А	А	А	А	А	А
				-	-	-
<- E	in 1	Ind	icat	tor		

C00 = Country	or Origin
---------------	-----------

AAA = Atmel Lot Number

11.4 8-Ultra Thin Mini-MAP

TOP MARK

	Y = YEAR OF ASSEMBLY
2 D B	XX = ATMEL LOT NUMBER TO COORESPOND WITH
	NSEB TRACE CODE LOG BOOK.
H 1	$(e.g. XX = AA, AB, AC, \dots AX, AY, AZ)$
Y X X	
	Y = SEAL YEAR
*	6: 2006 0: 2010
	7: 2007 1: 2011
Pin 1 Indicator (Dot)	8: 2008 2: 2012
	9: 2009 3: 2013

11.5 8-ULA

TOP MARK

Y = YEAR OF ASSEMBLY

11.6 dBGA2

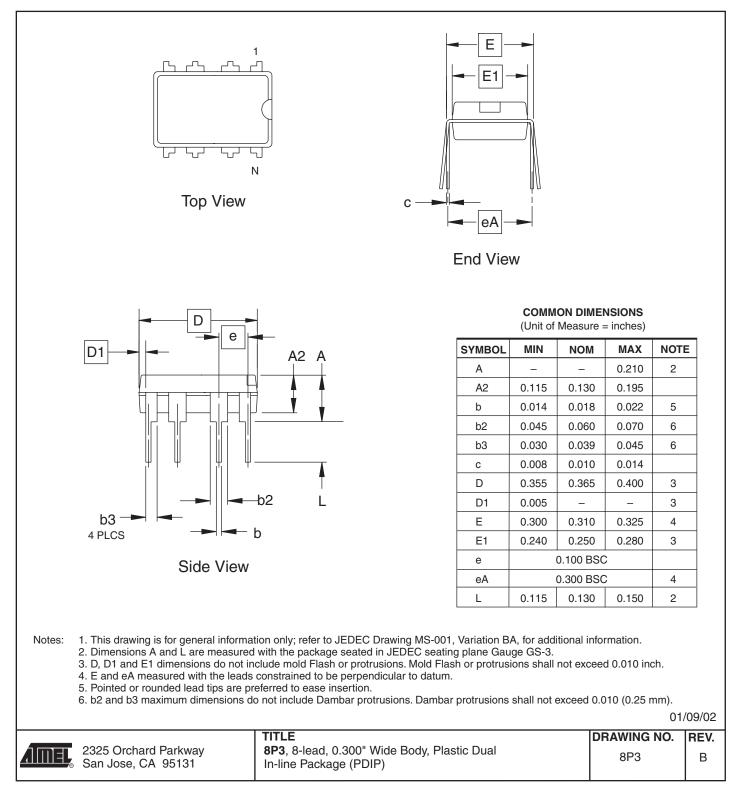
TOP MARK LINE 1----> 2DBU LINE 2----> PYMTC |<-- Pin 1 This Corner</pre> P = COUNTRY OF ORIGIN Y = ONE DIGIT YEAR CODE 4: 2004 7: 2007 5: 2005 8: 2008 6: 2006 9: 2009 M = SEAL MONTH (USE ALPHA DESIGNATOR A-L) A = JANUARYB = FEBRUARY J = OCTOBER K = NOVEMBER L = DECEMBERTC = TRACE CODE (ATMEL LOT

TC = TRACE CODE (ATMEL LOT NUMBERS TO CORRESPOND WITH ATK TRACE CODE LOG BOOK)

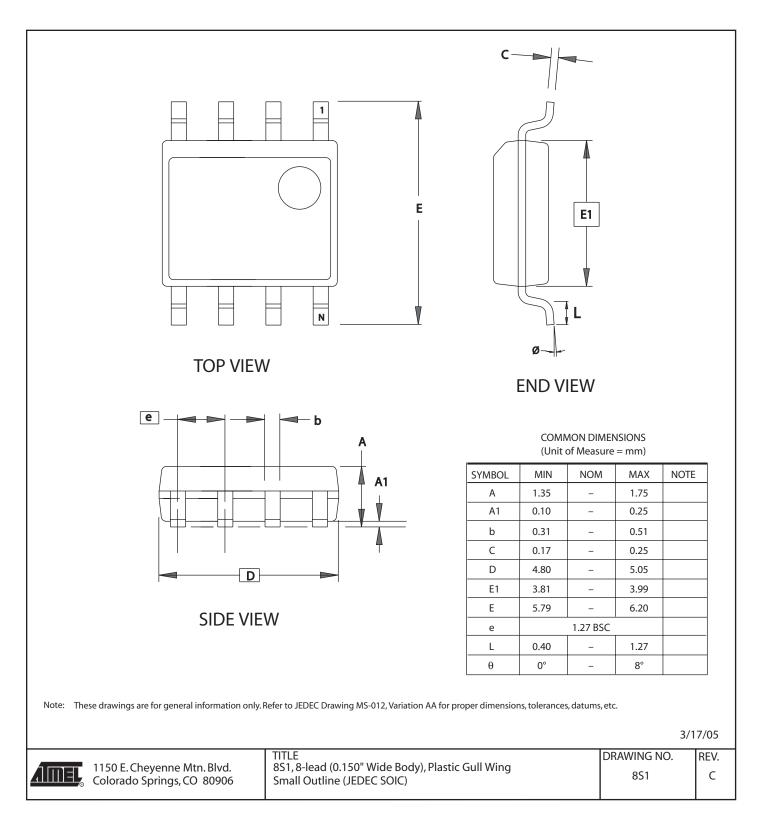




8P3 – PDIP



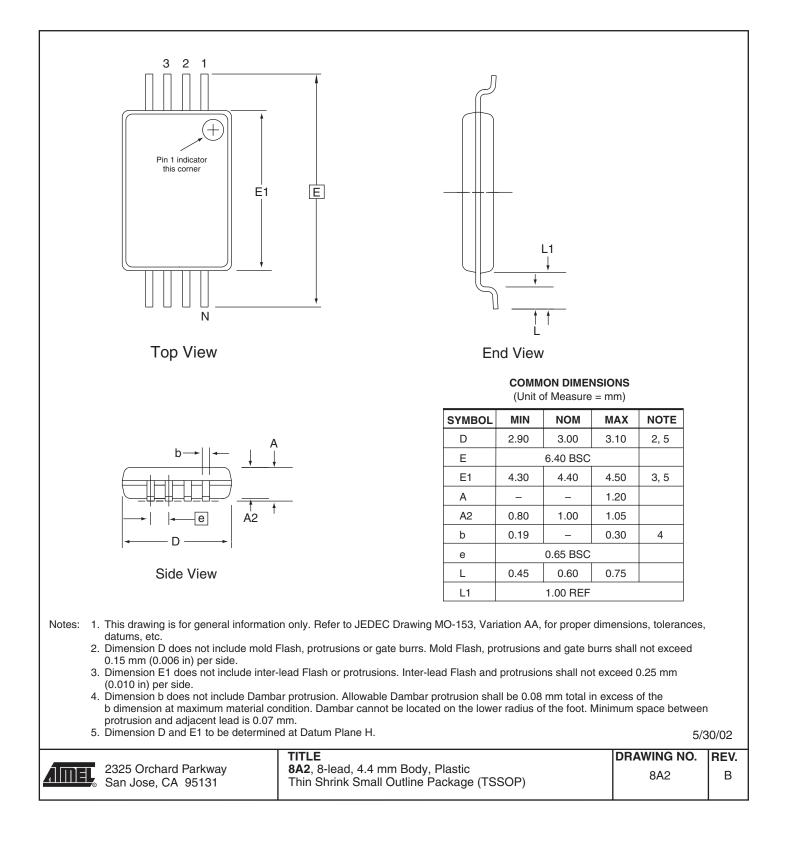
8S1 - JEDEC SOIC



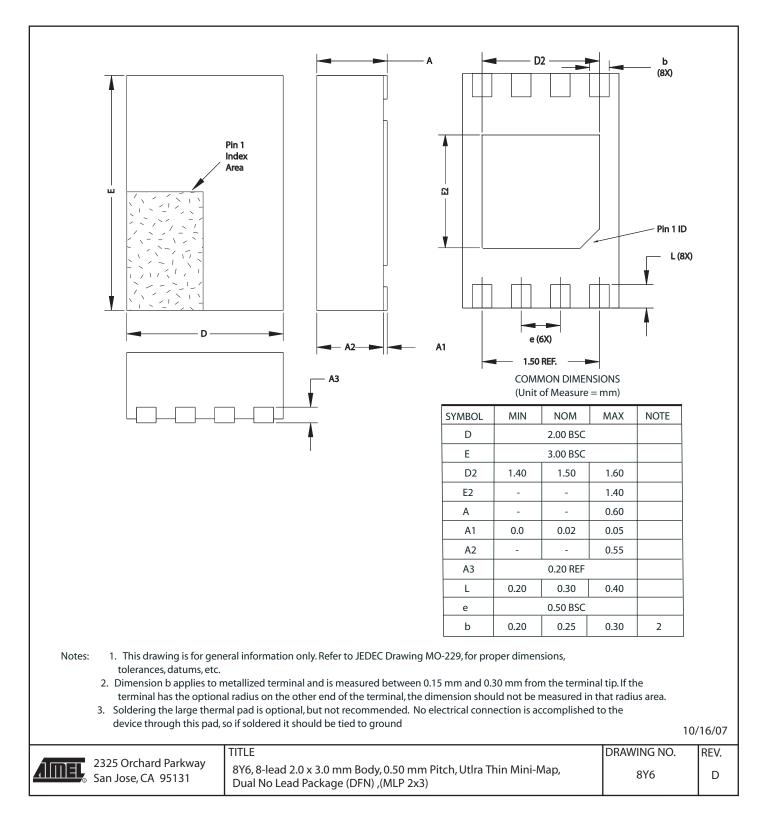




8A2 - TSSOP



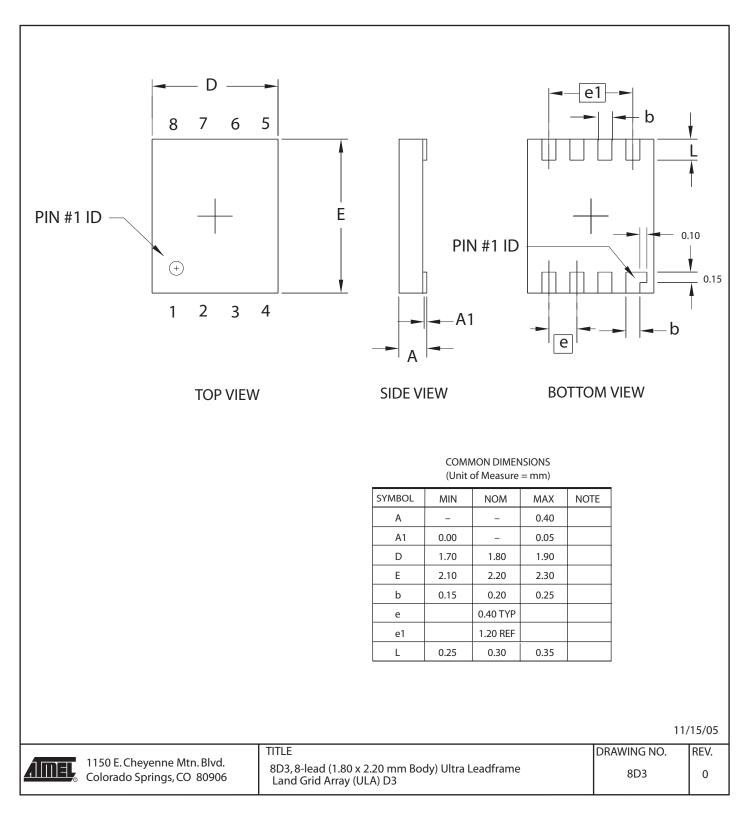
8Y6 – MAP





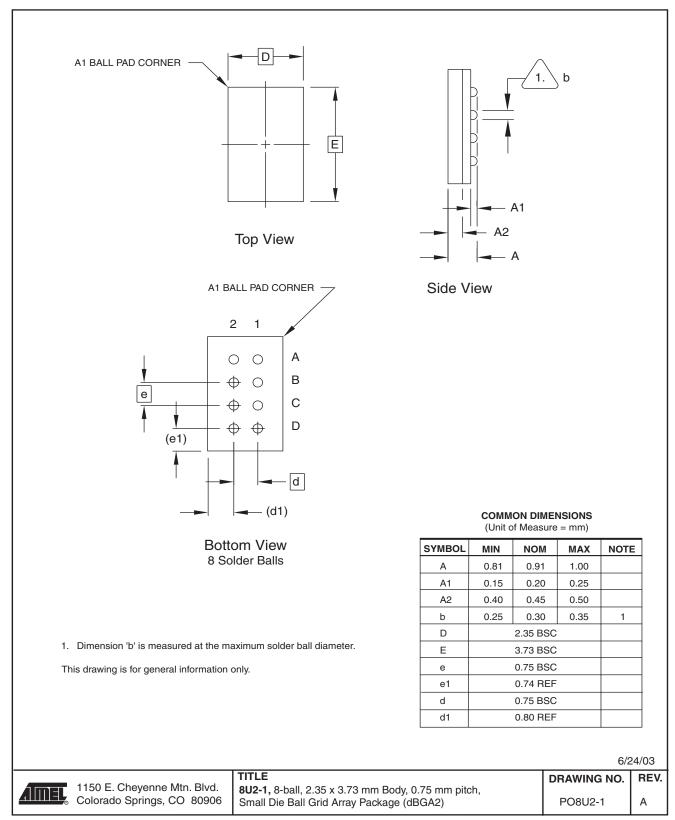


8D3 - ULA



AT24C128B

8U2-1 - dBGA2







Revision History

Doc. Rev.	Date	Comments
5296A	1/2008	AT24C128B product with date code 2008 work week 14 (814) or later supports 5Vcc operation Initial document release